

The Second Generation of the PROTO AXRD Benchtop Diffraction System

Author(s):

Dr. Nicholas Vukotic* and Dr. Stanislav Veinberg

Affiliations:

PROTO Manufacturing Ltd.

Abstract:

The PROTO AXRD Benchtop Diffraction system provides fast data collection with high resolution and provides unique solutions to customers around the globe. Utilizing advanced hybrid photon counting detection with superb low angle capabilities and excellent angular accuracy throughout the entire angular range. This paper will describe the new features implemented in the second generation of the AXRD Benchtop system. Highlights will include I) Thin film analysis, II) Variable temperature collection, and III) Non-ambient diffraction experiments performed under high gas pressure.

